



# CED04N6/CEU04N6

## N-Channel Enhancement Mode Field Effect Transistor

PRELIMINARY

### FEATURES

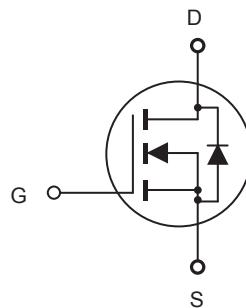
- 600V, 3.4A,  $R_{DS(ON)} = 2.4\Omega$  @ $V_{GS} = 10V$ .
- Super high dense cell design for extremely low  $R_{DS(ON)}$ .
- High power and current handing capability.
- Lead-free plating ; RoHS compliant.
- TO-251 & TO-252 package.



CEU SERIES  
TO-252(D-PAK)



CED SERIES  
TO-251(I-PAK)



### ABSOLUTE MAXIMUM RATINGS $T_C = 25^\circ C$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	$V_{DS}$	600	V
Gate-Source Voltage	$V_{GS}$	$\pm 30$	V
Drain Current-Continuous @ $T_C = 25^\circ C$ @ $T_C = 100^\circ C$	$I_D$	3.4	A
		2.2	A
Drain Current-Pulsed <sup>a</sup>	$I_{DM}$	13.6	A
Maximum Power Dissipation @ $T_C = 25^\circ C$ - Derate above $25^\circ C$	$P_D$	70	W
		0.56	W/ $^\circ C$
Single Pulsed Avalanche Energy <sup>e</sup>	$E_{AS}$	242	mJ
Single Pulsed Avalanche Current <sup>e</sup>	$I_{AS}$	4.4	A
Operating and Store Temperature Range	$T_J, T_{stg}$	-55 to 150	$^\circ C$

### Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.8	$^\circ C/W$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	50	$^\circ C/W$

This is preliminary information on a new product in development now .  
Details are subject to change without notice .

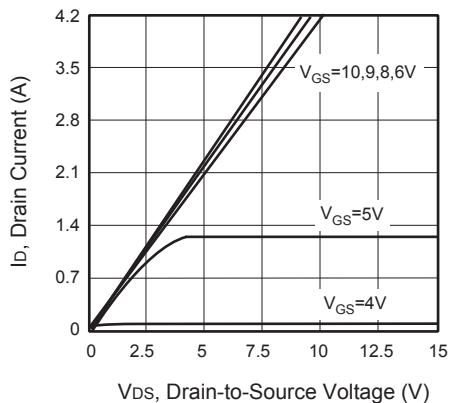
Rev 1. 2012.Oct  
<http://www.cet-mos.com>



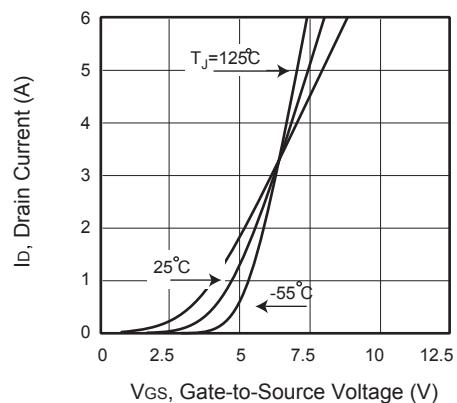
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## Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

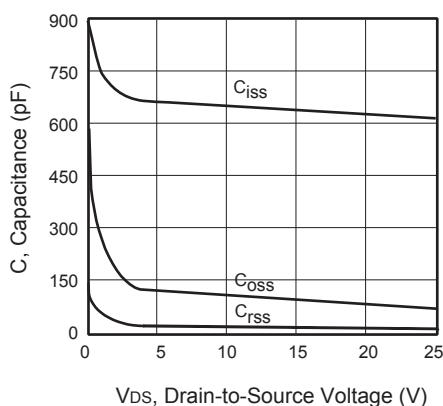
Parameter	Symbol	Test Condition	Min	Typ	Max	Units
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_{\text{D}} = 250\mu\text{A}$	600			V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 600\text{V}, V_{\text{GS}} = 0\text{V}$		1		$\mu\text{A}$
Gate Body Leakage Current, Forward	$I_{\text{GSSF}}$	$V_{\text{GS}} = 30\text{V}, V_{\text{DS}} = 0\text{V}$		100		nA
Gate Body Leakage Current, Reverse	$I_{\text{GSSR}}$	$V_{\text{GS}} = -30\text{V}, V_{\text{DS}} = 0\text{V}$		-100		nA
<b>On Characteristics<sup>b</sup></b>						
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}} = V_{\text{DS}}, I_{\text{D}} = 250\mu\text{A}$	2		4	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_{\text{D}} = 1.7\text{A}$		2	2.4	$\Omega$
<b>Dynamic Characteristics<sup>c</sup></b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}} = 25\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		605		pF
Output Capacitance	$C_{\text{oss}}$			75		pF
Reverse Transfer Capacitance	$C_{\text{rss}}$			15		pF
<b>Switching Characteristics<sup>c</sup></b>						
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 300\text{V}, I_{\text{D}} = 4\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 25\Omega$		18		ns
Turn-On Rise Time	$t_{\text{r}}$			18		ns
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$			33		ns
Turn-Off Fall Time	$t_{\text{f}}$			13		ns
Total Gate Charge	$Q_{\text{g}}$	$V_{\text{DS}} = 480\text{V}, I_{\text{D}} = 4\text{A}, V_{\text{GS}} = 10\text{V}$		12		nC
Gate-Source Charge	$Q_{\text{gs}}$			3		nC
Gate-Drain Charge	$Q_{\text{gd}}$			5		nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
Drain-Source Diode Forward Current	$I_{\text{S}}$				3.4	A
Drain-Source Diode Forward Voltage <sup>b</sup>	$V_{\text{SD}}$	$V_{\text{GS}} = 0\text{V}, I_{\text{S}} = 3.4\text{A}$			1.2	V
<b>Notes :</b>						
a.Repetitive Rating : Pulse width limited by maximum junction temperature. b.Device Mounted on FR4 Board, $t < 10 \text{ sec.}$ c.Pulse Test : Pulse Width $\leq 300\mu\text{s}$ , Duty Cycle $\leq 2\%$ . d.Guaranteed by design, not subject to production testing. e.L = 25mH, $I_{\text{AS}} = 4.4\text{A}$ , $V_{\text{DD}} = 50\text{V}$ , $R_{\text{G}} = 25\Omega$ , Starting $T_J = 25^\circ\text{C}$						



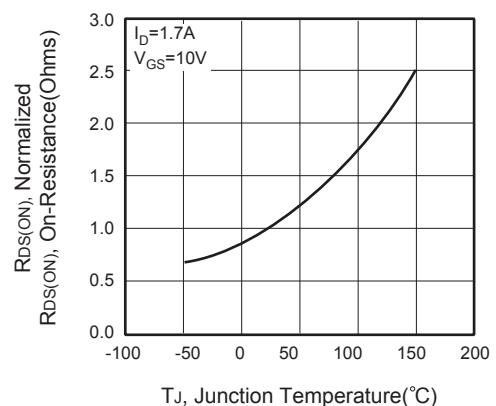
**Figure 1. Output Characteristics**



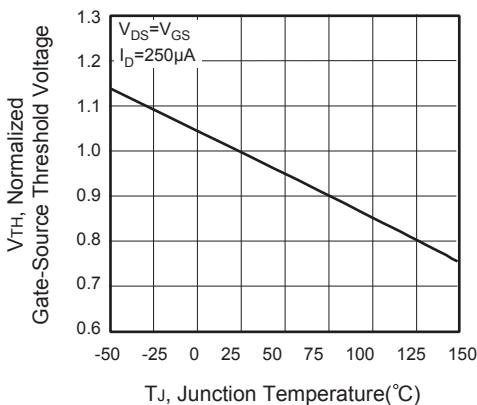
**Figure 2. Transfer Characteristics**



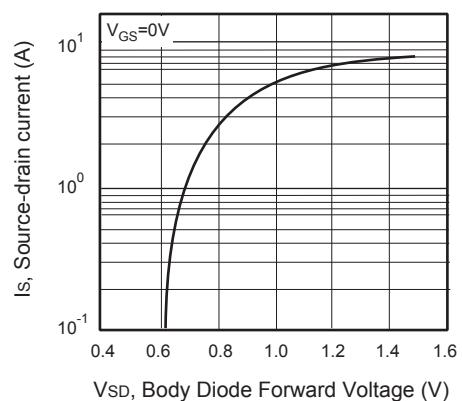
**Figure 3. Capacitance**



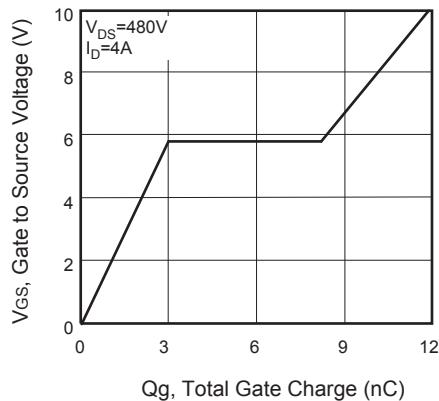
**Figure 4. On-Resistance Variation with Temperature**



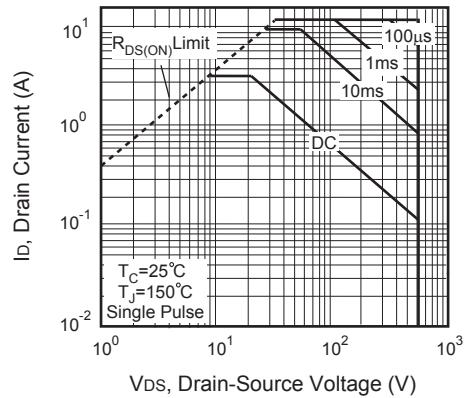
**Figure 5. Gate Threshold Variation with Temperature**



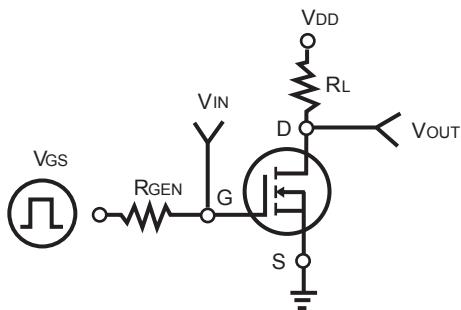
**Figure 6. Body Diode Forward Voltage Variation with Source Current**



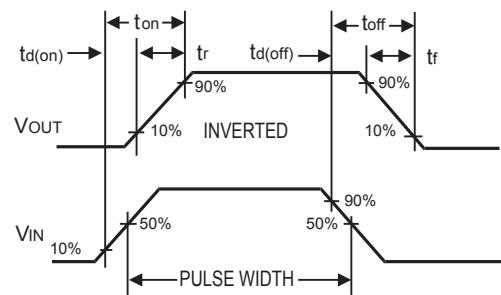
**Figure 7. Gate Charge**



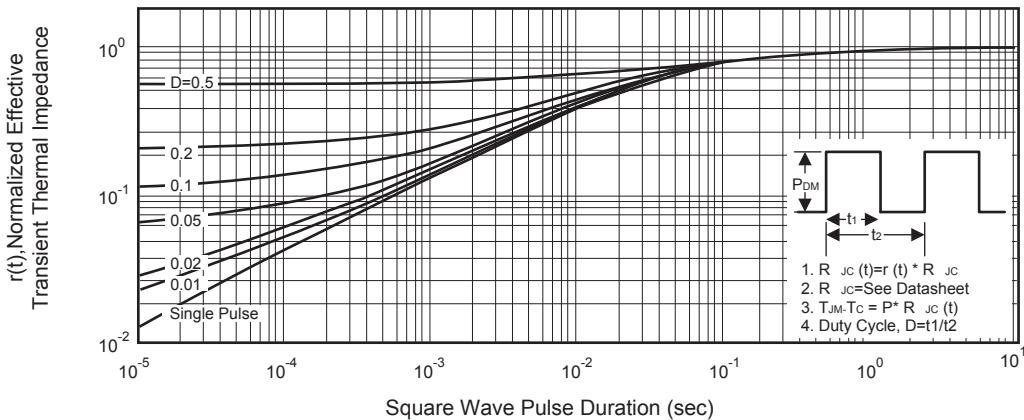
**Figure 8. Maximum Safe Operating Area**



**Figure 9. Switching Test Circuit**



**Figure 10. Switching Waveforms**



**Figure 11. Normalized Thermal Transient Impedance Curve**